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2006 02 27  
**PATENT APPLICATION**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of

Docket No: Q91474

Hideyuki OHTAKE, et al.

Appln. No.: Based on PCT/JP04/012613

Confirmation No.: Not yet assigned

Group Art Unit: Not yet assigned

Filed: February 27, 2006

Examiner: Not yet assigned

For: ELECTRIC-FIELD DISTRIBUTION MEASUREMENT METHOD AND APPARATUS  
FOR SEMICONDUCTOR DEVICE

**PRELIMINARY AMENDMENT**

**MAIL STOP AMENDMENT**

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Sir:

Prior to examination, please amend the above-identified application as follows on the  
accompanying pages.

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